

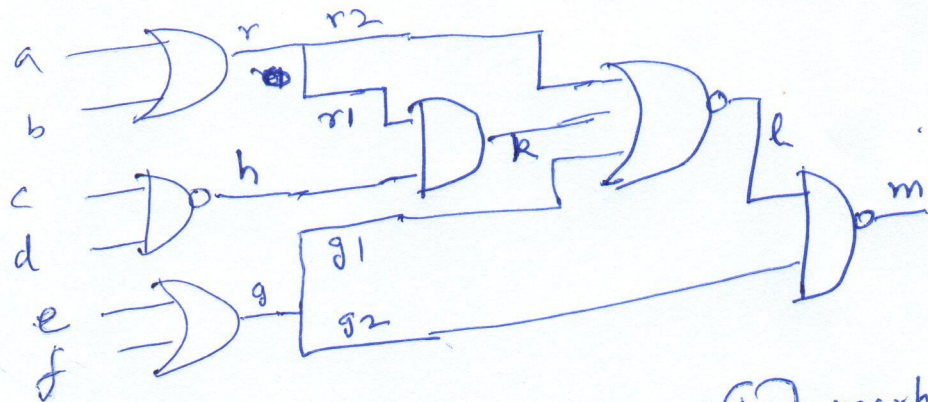
- ① Given a combinational circuit with only AND gate is it possible to generate

(a) an 0^* hazard (static hazard)

(b) an 1^* hazard (static hazard)

If yes, show an example. If no, prove the same. — (8) marks.

- ② Perform Deductive Simulation for the test vector $(a=1, b=0, c=1, d=0, e=1, f=1)$ and the fault $g_1: s-a-0, a: s-a-0, r1: s-a-1$



— (16) marks.

- ③ State the advantages of Event driven Simulation over Parallel Simulation — (2) marks.

- ④ When $(a=1, b=0, d=0)$ is applied on the following circuit, find the new Concurrent list of faults. — (5) marks

